



**Atomic Force Microscopy (AFM/SPM):** Atomic Force Microscopy (AFM) or Scanning Probe Microscopy (SPM) AIST-NT Smart SPM 1000, is a first 100% automated system that offers its cutting-edge technology of ultra-fast, metrological and high resolution measurements for the most advanced materials research at the nano scale in all AFM and STM modes. Various Measuring modes, Contact AFM in air/liquid; Semicontact AFM in air/liquid; Non-contact AFM; Phase Imaging; Magnetic Force Microscopy (MFM); Kelvin Probe (Surface Potential Microscopy); Electric Force Microscopy (EFM); Piezo Response Force Microscopy; Force curve measurements; Nanolithography; Conductive AFM; Scanning Tunneling Microscopy STM (optional); Photocurrent Mapping; Volt-ampere characteristic measurements.